In-situ hard x-ray microscopy of self-assembly in colloidal suspensions

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This supplementary information provides extended schematic representation of the µradXRD and the TXM setups and intensity profiles of the diffraction patterns in Figs 3-8 of the main text.

Fig. S1
Fig. S2. $I(q)$ profiles corresponding to Fig. 3A. Red squares correspond to vertical cut of the 2D pattern, green circles to horizontal cut.

Fig. S3. $I(q)$ profiles corresponding to Fig. 4A. Red squares is a cut of the 2D pattern through peaks originating from the smectic ordering in the system. Green circles is a cut through the broad peak.
Fig. S4. $I(q)$ profiles corresponding to Fig. 5A. Red squares correspond to the horizontal cut, green circles to the vertical cut.

Fig. S5. $I(q)$ profiles corresponding to Fig. 6A. Red squares is a cut through horizontal peaks, green circles is a cut from vertical peaks. Blue triangles and orange stars are cuts through higher order peaks.
Fig. S6. I(q) profiles corresponding to Fig. 7A. Red squares is a cut through vertical peaks, green circles is a diagonal cut.

![Graph](image1.png)

Fig. S7. I(q) profiles corresponding to Fig. 8A. Red squares is a cut through horizontal peaks, green circles is a cut from vertical peaks. Blue triangles and orange stars are cuts through higher order peaks. Blue triangles – diagonal cut.

![Graph](image2.png)